

# EMC TEST REPORT

For

Dongguan Lingjie Electronics & Technology Co., Ltd

Product Name: Gaming Mouse

Model No.: AGM600

Prepared for : Dongguan Lingjie Electronics & Technology Co., Ltd  
Address : Building A(Floor 1-4) and B(Floor 1-5), No. 16 Zhenxing North Road, Taiyuan Community, Xiegang Town, Dongguan City, Guangdong Province, 523590, P.R.C.

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Report No. : POCE220507008TRE  
Date of Receiver : Apr. 29, 2022  
Number of tested samples : 1  
Date of Test : Apr. 29, 2022–May 07, 2022  
Date of Report : May 07, 2022

*Note: This test report is limited to the above client company and the product model only. It may not be duplicated without prior written consent of Shenzhen POCE Technology Co., Ltd*

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## TABLE OF CONTENT

Description	Page
Test Report Description	
<b>1. GENERAL INFORMATION .....</b>	<b>4</b>
1.1. Description of Device (EUT).....	4
1.2. Test Standards .....	5
1.3. Test Methodology.....	5
1.4. Test Facility .....	5
<b>2. MEASURING DEVICE AND TEST EQUIPMENT .....</b>	<b>6</b>
2.1. For Power Line Conducted Emission .....	6
2.2. For Radiated Emission Measurement .....	6
2.3. For Harmonic Current / Flicker Measurement.....	6
2.4. For Electrostatic Discharge Immunity Test .....	6
2.5. For RF Strength Susceptibility Test.....	7
2.6. For Electrical Fast Transient /Burst Immunity Test.....	7
2.7. For Surge Immunity Test.....	7
2.8. For Injected Current Susceptibility Test.....	7
2.9. For Magnetic Field Immunity Test.....	7
2.10. For Voltage Dips and Interruptions Test.....	8
<b>3. POWER LINE CONDUCTED EMISSION MEASUREMENT .....</b>	<b>9</b>
3.1. Block Diagram of Test Setup.....	9
3.2. EUT Configuration on Measurement.....	9
3.3. Test Procedure .....	9
<b>4. RADIATED EMISSION MEASUREMENT.....</b>	<b>11</b>
4.1. Block Diagram of Test.....	11
4.2. Measuring Standard .....	11
4.3. EUT Configuration on Test.....	12
4.4. Test Procedure .....	12
<b>5. HARMONIC CURRENT EMISSION MEASUREMENT.....</b>	<b>15</b>
5.1 Block Diagram of Test Setup.....	15
5.2 Measuring Standard.....	15
5.3 Description of test Equipment.....	15
<b>6. VOLTAGE FLUCTUATION AND FLICKER MEASUREMENT.....</b>	<b>16</b>
6.1 Block Diagram of Test Setup.....	16
6.2 Measuring Standard .....	16
<b>7. ELECTROSTATIC DISCHARGE IMMUNITY TEST .....</b>	<b>17</b>
7.1 Block Diagram of Test Setup .....	17
7.2 Test Standard .....	17
7.3 Severity Levels and Performance Criterion .....	17
7.4 Test Procedure .....	18
<b>8. RF FIELD STRENGTH SUSCEPTIBILITY TEST .....</b>	<b>20</b>
8.1 Block Diagram of Test.....	20
8.2 Test Standard.....	20
8.3 Severity Levels and Performance Criterion.....	21
8.4 Test Procedure .....	21
<b>9. ELECTRICAL FAST TRANSIENT/BURST IMMUNITY TEST .....</b>	<b>23</b>
9.1 Block Diagram of Test Setup .....	23
9.2 Test Standard .....	23
9.3 Severity Levels and Performance Criterion .....	23

9.4 Test Procedure .....	24
Note: N/A denotes test is not applicable in this test report.....	24
<b>10. SURGE IMMUNITY TEST.....</b>	<b>25</b>
10.1 Block Diagram of Test Setup .....	25
10.2 Test Standard .....	25
10.3 Severity Levels and Performance Criterion .....	25
10.4 Test Procedure .....	26
Note: N/A denotes test is not applicable in this test report.....	26
<b>11. INJECTED CURRENTS SUSCEPTIBILITY TEST .....</b>	<b>27</b>
11.1 Block Diagram of Test Setup.....	27
11.2 Test Standard .....	27
11.3 Severity Levels and Performance Criterion.....	27
11.4 Test Procedure .....	28
Note: N/A denotes test is not applicable in this test report.....	28
<b>12. MAGNETIC FIELD SUSCEPTIBILITY TEST .....</b>	<b>29</b>
12.1 Block Diagram of Test .....	29
12.2 Test Standard .....	29
12.3 Severity Levels and Performance Criterion .....	29
12.4 Test Procedure .....	29
<b>13. VOLTAGE DIPS AND INTERRUPTIONS TEST .....</b>	<b>31</b>
13.1 Block Diagram of Test Setup .....	31
13.2 Test Standard .....	31
13.3 Severity Levels and Performance Criterion .....	32
13.4 Test Procedure .....	32
Note: N/A denotes test is not applicable in this test report.....	32
<b>14. PHOTOGRAPH .....</b>	<b>33</b>
14.1 Photo of Radiated Emission .....	33
<b>15. PHOTOGRAPHS OF EUT.....</b>	<b>34</b>

## 1. GENERAL INFORMATION

### 1.1. Description of Device (EUT)

EUT : Gaming Mouse

Trade Mark : AOC

Model : AGM600

Supplementary Model(s) : AGM6\*\*\*\*\* (\*=A~Z,a~z,0~9/,or blank)

Test Voltage : DC 5V

Rating : Input: DC 5 V, 120MA

Applicant : Dongguan Lingjie Electronics & Technology Co., Ltd

Address : Building A(Floor 1-4) and B(Floor 1-5), No. 16 Zhenxing North Road, Taiyuan Community, Xiegang Town, Dongguan City, Guangdong Province, 523590, P.R.C.

Manufacturer : TPV Electronics (Fujian) Co., Ltd.

Address : Rongqiao Economic and Technological Development Zone, Fuqing City, Fujian Province, P.R.China

Test Standards : BS EN 55032:2015/A11:2020  
BS EN 55035:2017/A11:2020  
BS EN IEC 61000-3-2:2019/A1:2021  
BS EN 61000-3-3:2013/A1:2019

Test Result : PASS

Test Engineer :

Reviewed By :



## 1.2. Test Standards

Standard	Test Items	Test Results
BS EN 55032:2015/A11:2020	Power Line Conducted Emission Test (150KHz To 30MHz)	N/A
	Radiated Emission(30MHz To 1000MHz)	PASS
	Radiated Emission(1GHz To 6GHz)	N/A
BS EN IEC 61000-3-2:2019/A1:2021	Harmonic Current	N/A
BS EN 61000-3-3:2013+A1:2019	Voltage Fluctuation And Flicker	N/A
BS EN 61000-4-2:2009	Electrostatic Discharge Immunity	PASS
BS EN 61000-4-3:2006+A2:2010	Radiated Electromagnetic Fields Immunity (80MHz to 1GHz)	PASS
	Radiated Electromagnetic Fields Immunity (1800MHz to 5GHz)	PASS
BS EN 61000-4-4:2012	Electric Fast Transient Burst Immunity	N/A
BS EN 61000-4-5:2014+A1:2017	Surge Immunity	N/A
BS EN 61000-4-6:2014+AC:2015	Injected Currents Susceptibility Test	N/A
BS EN 61000-4-8:2010	Magnetic field susceptibility test	PASS
BS EN 61000-4-11:2004+A1:2017	Voltage Dips And Interruptions Immunity	N/A

Note: Pass Indicates that the test is applicable  
 N/A Indicates that the test is not applicable

## 1.3. Test Methodology

All measurements contained in this report were conducted with CISPR 16-1, radio disturbance and immunity measuring apparatus, and CISPR16-2, Method of measurement of disturbances and immunity.

All measurement required was performed at laboratory of Shenzhen POCE Technology Co., Ltd., at 101-102 Building H5 & 1/F., Building H, Hongfa Science & Technology Park, Tangtou, Shiyan, Bao'an District, Shenzhen, Guangdong, China

## 1.4. Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

The facility also complies with the radiated and AC line conducted test site criteria set forth in CISPR 16-1, CISPR16-2.